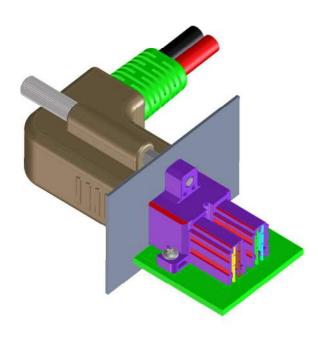
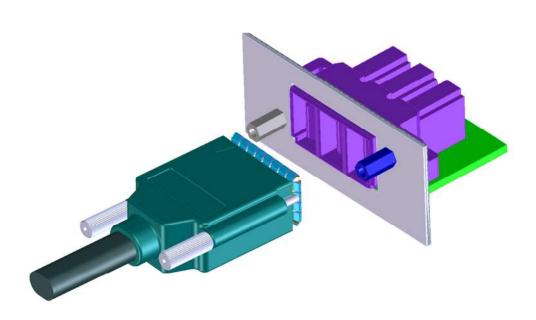


## **GUARDIAN CONNECTOR SYSTEM**





REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363  DATE: 2013/06/12		Guardian Wire to Board rconnect System	SHEET No. 1 of 19
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPROVED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PATEL
TEMPLATE ELLENAME: PRODUCT SPECISIZE ANALY 1) DOC				

## PRODUCT SPECIFICATION

### **TABLE OF CONTENTS:**

- 1.0 SCOPE
- 2.0 SUMMARY OF RESULTS
- 3.0 DOCUMENTS & SPECIFICATIONS
  - 3.1 Testing Procedure & Sequences
  - 3.2 Other Documents
- 4.0 MECHANICAL PERFORMANCE
  - 4.1 Component Level
  - 4.2 Free Hanging Load Test
- 5.0 ELECTRICAL REQUIREMENTS
  - 5.1 Crimp Stress Test-Millivolt Drop
  - **5.1.1 Crimp Stress Acceptance Criteria**
  - 5.2 Electrical Performance and Rating
  - 5.3 Temperature Rise Current Charts
- 6.0 TEST PLAN, ENVIRONMENTAL TEST PER EIA-364-1000.01
- 7.0 TEST RESULTS, ENVIRONMENTAL TESTING
- 8.0 SOLDER PROFILE
- 9.0 SAFETY AGENCY RATING APPROVAL
  - 9.1 C.S.A. File Number LR 19980 9.2 U.L. File Number – E29179

C4	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12		Guardian Wire to Board rconnect System		2 of 19
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PATEL	
TEMPLATE FILENAME: PRODUCT_SPEC[SIZE_A](V.1).DOC					

## PRODUCT SPECIFICATION

#### 1.0 SCOPE

The specification covers the test sequence performance of the high current wire-to-board interconnect system:

#### 2.0 SUMMARY OF RESULTS

The product meets all the Mechanical, Electrical and Environmental test criteria at component and harness level, and is considered a qualified product.

#### 3.0 DOCUMENTS AND SPECIFICATIONS

### 3.1 Testing Procedure & Sequences:

Item	Test Report	Test Description
1	TR-1.8582	Qualification Test Per EIA-364-1000 Group 1,2,3, & 5
2	TR-1.8583	Electrical Crimp Qualification of 8 & 10 AWG
3	TR-1.8584	Construction analysis
4	TR-1.8733	Harness Pull Force and Torque Retention Test, in mated condition
5	TR-1.8570	T-Rise Test per EIA-364B
6	TR-1.8595	Normal Force Analysis
7	63801-7900	Mech. Crimp Qualification
8		EIA-364-1000 Group 4 Mixed Flowing Gases
9	TR-1.8931	Hot-mating/Resistance to Arc

#### 3.2 Other Documents:

See series specific sales drawings for additional information.

HEADER	2 CKT	46817 SERIES
	3 CKT	46817 SERIES
HARNESS	2 CKT	68790 SERIES
HARNESS	3 CKT	111119 SERIES

Ref. terminal in harness - 46819-\*\*\*\*

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363  DATE: 2013/06/12		Guardian Wire to Board rconnect System		3 of 19
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER A.PATE		TEL
TEMPLATE FILENAME: PRODUCT_SPEC[SIZE_A](V.1).DOC					

## **PRODUCT SPECIFICATION**

## 4.0 MECHANICAL PERFORMANCE

### 4.1 MECHANICAL PERFORMANCE AT COMPONENT LEVEL

EQUIPMENT/FIXTURE	TEST DESCRIPTION			TEST	RES	ULT			
Force Gauge	Terminal Retention to the Housing (Header) per EIA-364-29		Avg.(3 (	<u> </u>				13.83 N 0.56	
Solder Pot	Solderability Test (Header) per EIA- 364-52		N	leets 95%	min (	Covera	age		
X-Ray Fluoroscope	Plating Verification (Plug & Crimp Terminal)	Meets Specification							
Instron	Normal Force per EIA-364-04, Method	3.90 g (Avg)/Beam @ 0.45 mm deflection							
		1 <sup>st</sup> Cycle	In	sertion Fo (Newtons			Withdrawal Force (Newtons)		
			1 ckt	2 ckt	3 c	kt	1 ckt	2 ckt	3 ckt
Instron	Insertion/Withdrawal Force per EIA-364-13	Min	7.23	11.27	26.7	71	6.86	10.31	28.21
motion		Max	9.23	19.11	36.6	60	8.53	19.12	34.39
		Avg	7.92	15.60	31.0	06	7.36	15.87	30.75
		Std Dev	0.68	3.15	3.7	0	0.68	3.85	2.20
Force Gauge	Crimp Terminal Retention to Housing				N/A ermol	d		-	
*On	3 ckt configuration, 1 of th	e ckts is ground	(pre-mate	e) Above for	rces a	re peak	k force.		
						6 A\	WG	8 AWG	10 AW
Force Gauge	Crimp Torminal to Wi	ro Dull Force ("	20)	Avg (lbs)		31	5	302	216
roice Gauge	Crimp Terminal to Wi	e Full Force (II	J5)	Std De	٧٠.	11.	17	5.06	4.45
				Failure M	ode	Wi Pull-	-	Wire Break	Wire Break
C4 ECR/ECN INF				uardian to Boa					EET No. of <b>19</b>

C4	EC No: UCP2013-5363  DATE: 2013/06/12	Wire to Board Interconnect System			<b>4</b> of <b>19</b>
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	<u>APPROV</u>	'ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PATEL	
TEMPLATE FILENAME: PRODUCT_SPEC[SIZE_A](V.1).DOC					



## 4.2 MECHANICAL TEST: FREE HANGING LOAD TEST (MATED CONDITION - 2.5 M CABLE)

EQUIPMENT/FIXTURE	TEST DESCRIPTION	TEST RESULT
Rigid Fixture	100 Newtons Weight Straight Inline Loading For 60 Seconds (See Figure 1)	Visually Inspected No Damage
Rigid Fixture	200 Newtons Weight at 90 degrees Loading For 60 Seconds (Both North-South and East-West directions – see Figure 2)	Visually Inspected No Damage
Rigid Fixture	150 Newtons Weight 45 degrees loading For 60 Seconds (See Figure 3)	Visually Inspected No Damage







<u>Fig. 1</u> <u>Fig. 2</u> <u>Fig. 3</u>

### 5.0 ELECTRICAL REQUIREMENTS

#### **5.1 CRIMP STRESS TEST-MILLIVOLT DROP**

CRIMP WIRE SIZE	TEST DESCRIPTION	SAMPLE SIZE	Δ RESULT
	<ul><li>Initial Voltage Drop</li><li>Thermal Shock</li><li>Vibration</li></ul>	Qty 75 Nominal Crimp Height (Grp A)	0.30 Millivolts $\sigma = 0.053$
8 AWG	<ul><li>Accelerated Aging</li><li>Final Voltage Drop</li><li>End Testing</li></ul>	Qty 30 Upper Crimp Height (Grp. B)	$0.20$ Millivolts $\sigma = 0.045$
	Applied 10 Amps See Figure 4 & 5 for test setup and measurements	Qty 30 Lower Crimp Height (Grp C)	$0.45$ Millivolts $\sigma = 0.101$

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363  DATE: 2013/06/12		Guardian Wire to Board rconnect System		5 of 19
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PATEL	
TEMPLATE FILENAME: PRODUCT SPECISIZE A1/V 1) DOC					

TEMPLATE FILENAME: PRODUCT\_SPEC[SIZE\_A](V.1).DOG



10 AWG	<ul><li>Initial Voltage Drop</li><li>Thermal Shock</li><li>Vibration</li></ul>	Qty 75 Nominal Crimp Height. (Grp A)	$0.66$ Millivolts $\sigma = 0.118$
	<ul> <li>Accelerated Aging</li> <li>Final Voltage Drop</li> <li>End Testing</li> </ul>	Qty 30 Upper Crimp Height (Grp. B)	$0.76$ Millivolts $\sigma = 0.177$
	Applied 10 Amps See Figures 4 & 5 for test set-up and measurements	Qty 30 Lower Crimp Height (Grp C)	0.56 Millivolts σ =0.120

<sup>\*</sup> Acceptance criteria appears on page 4 of this specification

#### **5.1.1 CRIMP STRESS ACCEPTANCE CRITERIA**

 $\Delta$  = Change in Millivolts after test sequence

 $\sigma$  = Standard Deviation

Requirements to pass 8 AWG wire:

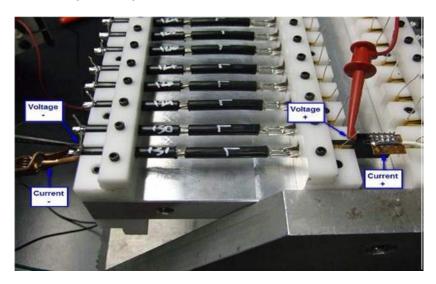
 $\Delta$  = Average Change + 5.46  $\sigma$  </= 1.33 Millivolt (Group A)

 $\Delta$  = Average Change + 4.21  $\sigma$  </= 1.33 Millivolt (Group B & C)

Requirements to pass 10 AWG wire:

 $\Delta$  = Average Change + 5.46  $\sigma$  </= 1.68 Millivolt (Group A)

 $\Delta$  = Average Change + 4.21  $\sigma$  </= 1.68 Millivolt (Group B & C)



Test Set-up Fig. 4

C4	ECR/ECN INFORMATION: EC No: UCP2013-5363  DATE: 2013/06/12		Guardian Wire to Board rconnect System		6 of 19
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PATEL	
TEMPLATE FILENAME: PRODUCT_SPEC[SIZE_A](V.1).DOC					

## PRODUCT SPECIFICATION

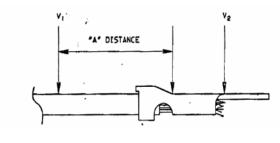


Fig. 5 Voltage Drop

The specimen wire gauge used for testing was 10 AWG. The specimen was powered at 10 amps. Voltage drop measurements were taken after 30 seconds across individual circuits at the applied current. The maximum allowable distance 'A' between the voltage probes was 100 mm. The open circuit voltage may not exceed 0.05 volts. Instrumentation shall be such that the measured value is accurate to +/- 5%.

#### 5.2 ELECTRICAL PERFORMANCE & RATING:

#### **5.2.1 VOLTAGE:**

Voltage: 600 V Max.

#### Connector Rating per UL-1977

Connector voltage rating meets the connector approval level defined by UL 1977, Sect. 11 for spacing's per table 11.1. Example: 1.2 mm for ≥ 250 volt, 3.2 mm for ≤ 250 volt.

Exception taken for spacing less than those specified are permitted if the device complies with the requirements in the dielectric voltage withstanding test per Sect. 17.

### **Application Voltage Guideline**

For application voltage requirements per UL-60950 or other standards, the creepage & clearance also needs to be determined based upon pads/traces on the pcb. For example, per UL-60950-1 (Table 2N) (UL/ANSI Standard-Safety for Information Technology Equipment Requirements) below are the minimum creepage distances required:

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12		Guardian Wire to Board rconnect System		7 of <b>19</b>
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	<u>APPROV</u>	/ED BY:
PS	-46819-001	J.QUILES	J.SCHAFER	A.PA	TEL
			TEMPLATE ELLENIAN	AE, DEODUCT CRECI	CIZE 41/1/4) DOC



		POLLUTION	DEGREE 2				
RMS Working		MATERIAL GROUP					
Voltages Up to & Including:	PRINTED CIRCUIT BOARDS	OTHER MATERIALS					
(V)	I, II, IIIa, IIIb (mm)	l (mm)	II (mm)	IIIa, IIIb (mm)			
50	.04	0.6	0.85	1.2			
125	.25	0.75	1.05	1.5			
250	1.0	1.25	1.8	2.5			
320	1.6	1.6	2.2	3.2			
630	3.2	3.2	4.5	6.3			

- \*Pollution degree 2 is a typical environment for electrical connectors.
- \*\*Material Group depends on the comparative tracking index (CTI) and is classified as follows:

Material Group I  $CTI \ge 600$ Material Group II  $400 \le CTI < 600$ Material Group IIIA  $175 \le CTI < 400$ Material Group IIIB  $100 \le CTI < 175$ 

## **5.2.2 OPERATING TEMPERATURE**

Operating temperature (including T-rise from applied current) is -40°C to +105°C. Field temperatures and field life: Tested per EIA-364-1000.01 (see pg 14) to meet field temperature of 65° C for 10 years or 85° C for 3 years per Tables 8 & 9 application guideline.

#### **5.2.3 CURRENT:** (See Item #4)

Current rating is application dependent. The ratings listed in the chart are per EIA364-70 and should be used as a guideline only. Appropriate de-rating is required per ckt size, ambient conditions, copper trace size on the PCB, gross heating from adjacent modules or components, and other factors that influence connector performance. Wire size and stranding, tin coated or bare copper, wire length & crimp quality are other factors that influence current rating

#### 5.2.4 DURABILITY WITH ENVIRONMENT:

25 cycles on EIA 364-1000.01 Group 4 Test sequence.

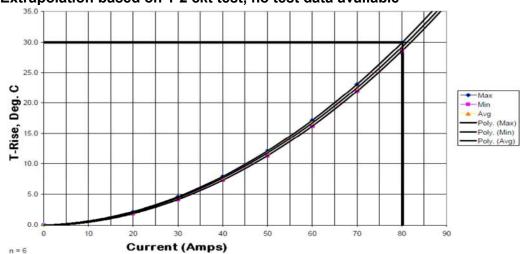
REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363  DATE: 2013/06/12		Guardian Wire to Board rconnect System		8 of <b>19</b>
DOCUMENT I	NUMBER:	CREATED / REVISED BY:	CHECKED BY:	CHECKED BY: APPROVED BY:	
PS-46819-001		J.QUILES	J.SCHAFER	ER A.PATEL	
	TEMPLATE FILENAME: PRODUCT SPECISIZE AI(V.1), DOC				

## PRODUCT SPECIFICATION

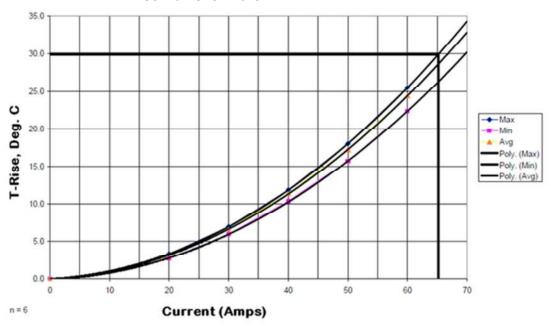
#### 5.3 TEMPERATURE RISE & VOLTAGE DROP CHARTS

## 5.3.1 EPIC, 1-Circuit, 6 AWG Wire, 0.050" Cu T-Rise Current Chart

\*Extrapolation based on 1-2 ckt test, no test data available



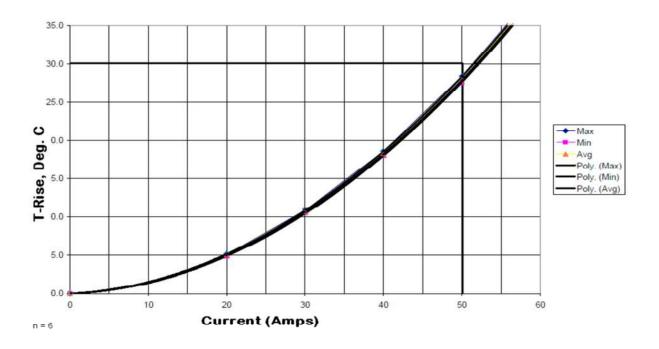
### 5.3.2 EPIC, 1-circuit, 8 AWG Wire, 0.032" Cu T-Rise Current Chart



REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12		Guardian Wire to Board rconnect System		9 of 19
DOCUMENT I	NUMBER:	CREATED / REVISED BY:	CHECKED BY:	CHECKED BY: APPROVED BY	
PS	-46819-001	J.QUILES	J.SCHAFER	A.PA	TEL
			ΤΕΜΡΙ ΔΤΕ ΕΙΙ ΕΝΙΔΙ	AE PRODUCT SPEC	ISIZE AI(V 1) DOC



## 5.3.3 EPIC, 1-circuit, 10 AWG Wire, 0.026" Cu T-Rise Current Chart



REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12	Wire to Board Interconnect System		10	of <b>19</b>
DOCUMENT I	NUMBER:	CREATED / REVISED BY: CHECKED BY: APPROVE		APPROVED B	3Y:
PS	-46819-001	J.QUILES	J.SCHAFER	A.PATEL	
			TEMPI ATE EII ENIAN	ME DOODLICT SPECISIZE AT	1/V 1) DOC



## 5.3.4 EPIC, 2-Circuit, 8 AWG Wire, 0.032" Cu Voltage Drop vs. Current

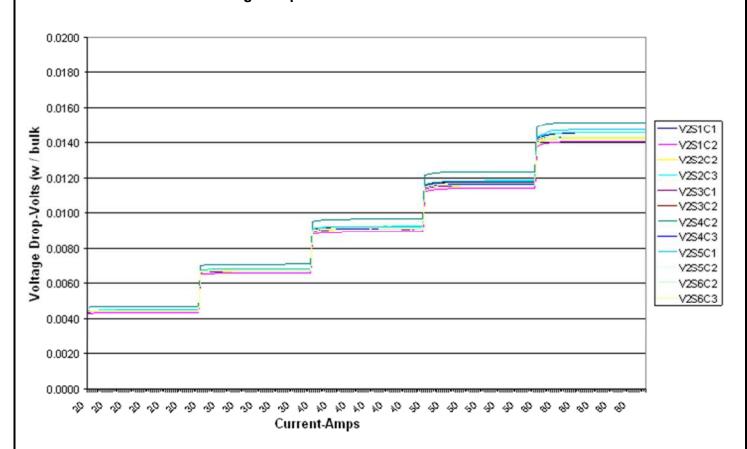


Fig. 6

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12	Guardian Wire to Board Interconnect System			SHEET No. 11 of 19
DOCUMENT I	NUMBER:	CREATED / REVISED BY: CHECKED BY: APPROV		APPRO\	<u>/ED BY:</u>
PS-46819-001		J.QUILES	J.SCHAFER	A.PA	TEL

TEMPLATE FILENAME: PRODUCT\_SPEC[SIZE\_A](V.1).DOC



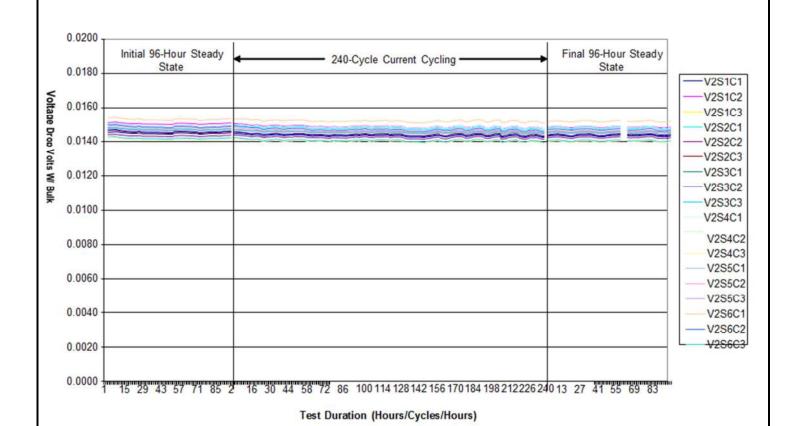


Fig. 7

NOTE: Current Cycle Duration is 1 hour (45 minutes on and 15 minutes off)

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363  DATE: 2013/06/12		Guardian Wire to Board rconnect System		12 of 19
DOCUMENT I	NUMBER:	CREATED / REVISED BY:	CHECKED BY:	CHECKED BY: APPROVED BY:	
PS	-46819-001	J.QUILES	J.SCHAFER	A.PATEL	
	TEMPLATE FILENAME: PRODUCT_SPECISIZE_AI(V_1)_DOC				

DOCUMENT NUMBER:

PS-46819-001

## PRODUCT SPECIFICATION

## 6.0 TEST PLAN, ENVIRONMENTAL TEST PER EIA-364-1000.01 - Table 8

Group Temperatur (30 conta	re Life	Group II Thermal Sho (30 contact		Group III Vibration (30 contacts)	Group IV Flowing Mixed Gas (402 contacts)	Group V Thermal Cycling (30 contacts)
Initial Con Resistan		Initial Contac Resistance		Initial Contact Resistance	Initial Contact Resistance	Initial Contact Resistance
EIA-364-	-23	EIA-364-23	3	EIA-364-23	EIA-364-23	EIA-364-23
Durabili 5 cycle		Durability 5 cycles		Durability 5 cycles	Durability 5 cycles	Durability 5 cycles
EIA-364-	-09	EIA-364-09	)	EIA-364-09	EIA-364-09	EIA-364-09
Contact Res	istance	Contact Resista	ance	Contact Resistance	Contact Resistance	Contact Resistance
Temperatur 105°C, 240 10 Yrs @ 0	hours	Thermal Sho 10 cycles -55°C and +85		Temperature Life 105°C, 120 hours 10 Yrs @ 65°C	Temperature Life 105°C, 120 hours 10 Yrs @ 65°C	Temperature Life 105°C, 120 hours 10 Yrs @ 65°C
EIA-364-	-17	EIA-364-32	2	EIA-364-17	EIA-364-17	EIA-364-17
Contact Res	istance	Contact Resista	ance	Contact Resistance	Contact Resistance	Contact Resistance
Reseati		Cyclic Tempera and Humidit		Random Vibration	Flowing Mixed Gas 10 days unmated	Thermal Cycling
3 cycle	:S	EIA-364-31		EIA-364-28 Condition VIID	EIA-364-65	EIA-364-1000.01
Contact Res	istance	Contact Resista	ance	Contact Resistance	Contact Resistance	Contact Resistance
		Reseating 3 cycles			Flowing Mixed Gas 4 days mated EIA-364-65	Reseating 3 cycles
		Contact Resista	ance		Contact Resistance	Contact Resistance
					Thermal Disturbance	
					EIA-364-1000.01	
					Contact Resistance	
					Reseating 3 cycles	
					Contact Resistance	
REVISION:	ECD/ECN	INFORMATION:	TITLE:		<b>.</b>	SHEET No.
		CP2013-5363	11166.		Guardian re to Board	13 of 19
<u> </u>	C4 DATE: 2013/06/12				onnect System	

CREATED / REVISED BY:

**J.QUILES** 

CHECKED BY:

J.SCHAFER

**APPROVED BY:** 

A.PATEL

TEMPLATE FILENAME: PRODUCT\_SPEC[SIZE\_A](V.1).DOC

## PRODUCT SPECIFICATION

## 7.0 TEST RESULTS, ENVIRONMENTAL TESTING - Table 9

	Initial	EIA-364-TS-1000 - Grou Initial Durability 5X	T. Life	Reseating 3X
	mΩ	ΔmΩ	$\Delta m\Omega$	ΔmΩ
Min	0.387	-0.010	0.001	0.002
Max	0.649	0.008	0.024	0.032
Avg	0.506	0.000	0.014	0.018
St. Dev.	0.081	0.004	0.006	0.007
n	36	36	36	36

	EIA-364-TS-1000 - Group 2 Testing								
	Initial	Durability 5X	Durability 5X T. Shock		Reseating 3X				
	mΩ	ΔmΩ	ΔmΩ	ΔmΩ	ΔmΩ				
Min	0.419	-0.054	-0.056	-0.050	-0.039				
Max	0.681	0.155	0.163	0.156	0.162				
Avg	0.490	0.012	0.017	0.020	0.019				
St. Dev.	0.066	0.046	0.047	0.045	0.044				
n	36	36	36	36	36				

EIA-364-TS-1000 - Group 3 Testing							
	Initial	Initial Durability 5X		Random Vibration			
TO STATE OF THE PARTY OF THE PA	mΩ	ΔmΩ	ΔmΩ	ΔmΩ			
Min	0.374	-0.007	0.004	-0.010			
Max	0.651	0.013	0.028	0.041			
Avg	0.524	0.001	0.017	0.009			
St. Dev.	0.073	0.004	0.005	0.011			
n	36	36	36	36			

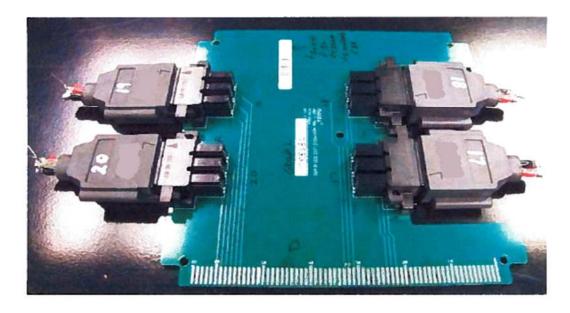
	EIA-364-TS-1000 - Group 5 Testing							
	Initial	Durability 5X	T. Life	Thermal Cycling	Reseating 3X			
	mΩ	ΔmΩ	$\Delta m\Omega$	ΔmΩ	ΔmΩ			
Min	0.343	-0.006	0.007	-0.001	0.004			
Max	0.672	0.009	0.043	0.041	0.038			
Avg	0.504	0.000	0.019	0.010	0.019			
St. Dev.	0.093	0.003	0.007	0.008	0.010			
n	36	36	36	36	36			

<sup>\*</sup> Note: resistance includes bulk, interface and crimp. Above resistance data includes 0.24 milliohms for Power and 0.29 milliohms for ground from wire length 7 test set-up. See sample preparation detail on page 10 of this specification.

<sup>\*\*</sup> Applied current <1.0 Amp for LLCR

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12	Guardian Wire to Board Interconnect System		SHEET No. 14 of 19	
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PA	TEL
TEMPLATE FILENAME: PRODUCT_SPEC[SIZE_A](V.1).DOC					SIZE_A](V.1).DOC

## PRODUCT SPECIFICATION



Test Set-up for EIA-364-1000.01 Sequences 1, 2, 3 & 5

Fig. 10

#### **SAMPLE PREPARATION**

The headers were wave soldered onto the PC boards and cleaned in the parts washer. The plugs were common bussed so LLCR measurements could be made. Due to sample preparation there is some added bulk resistance added in the measurements. There is approximately 1.75 inches of 8 AWG for the power contacts and 1.75 inches of 10 AWG wire for the ground contacts. This contributes ~0.09 milliohms of bulk resistance to the power contact measures and ~0.144 milliohms to the ground measures. The measurement leads (pigtail) also add up to 0.15 milliohms of additional bulk for a total of around 0.24 milliohms power, and 0.29 milliohms ground (See Figure 10).

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12	- Guarulan			
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPROVED BY:	
PS-46819-001		J.QUILES	J.SCHAFER	A.PATEL	
TEMPLATE FILENAME, PRODUCT, SPECIFIZE AND A DOC					

TEMPLATE FILENAME: PRODUCT\_SPEC[SIZE\_A](V.1).DO

## PRODUCT SPECIFICATION

## **EIA-364-1000 Test Group 4**

Description: 3 circuit board mount plug and cable receptacle

**Reference Information** 

Environmental Test Methodology...

EIA-364-1000 (Test Group 4)

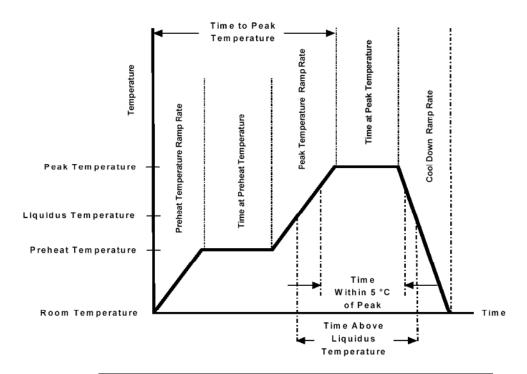
## **Contact Reliability**

Cell	Description	Conditions	Duration	Order	Samples
1	LLCR	4-wire, dry circuit, 20 mV max		1	1-134
	Durability (pre- conditioning)	mate / unmate	5 cycles	2	all
2	LLCR	4-wire, dry circuit, 20 mV max		3	all
	Temperature Life (pre-conditioning)	105C	120 hours	4	all
3	LLCR	4-wire, dry circuit, 20 mV max		5	all
	MFG Exposure	Unmated (board mount plugs only)	10 days	6	all
4	LLCR	4-wire, dry circuit, 20 mV max		7	all
	MFG Exposure	Mated	4 days	8	all
5	LLCR	4-wire, dry circuit, 20 mV max			
	Disturbance (ATC)	15C / 85C	10 cycles	9	all
6	LLCR	4-wire, dry circuit, 20 mV max		10	all
	Reseat **	mate / unmate	3 cycles	11	all
7	LLCR **	4-wire, dry circuit, 20 mV max		12	all

REVISION:	ECR/ECN INFORMATION:	TITLE:	Guardian		SHEET No.	
0.4	EC No: UCP2013-5363	,	Wire to Board		<b>16</b> of <b>19</b>	
C4	DATE: 2013/06/12		Interconnect System			
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:	
PS-46819-001		J.QUILES	J.SCHAFER	A.PA	TEL	
TEMPLATE FILENAME: PRODUCT_SPECISIZE_AI(V_1).DOC						

#### 8.0 **SOLDERING PROFILE**

(This profile is per JEDEC J-STD-020D.1 and it is for guide line only; please see notes for additional information)



Description	Requirement
Average Ramp Rate	3°C/sec Max
Preheat Temperature	150°C Min to 200°C Max
Preheat Time	60 to 180 sec
Ramp to Peak	3°C/sec Max
Time over Liquids (217°C)	60 to 150 sec
Peak Temperature	260 +0/-5°C
Time within 5°C of Peak	20 to 40 sec
Ramp - Cool Down	6°C/sec Max
Time 25°C to Peak	8 min Max

#### Note:

1. Temperature indicated refers to the PCB surface temperature at solder tail area.

#### THIS PRODUCT IS NOT DESIGNED FOR IR REFLOW PROCESS

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12	Guardian Wire to Board Interconnect System			
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PA	TEL
			TEMPLATE FILENAN	ME: PRODUCT_SPEC	SIZE AI(V.1).DOC

## PRODUCT SPECIFICATION

#### 9.0 SAFETY AGENCY RATING APPROVAL:

Covers product series 46817, 46818, 170351



9.1

IS File Number\*: LR-19980

Single Ckt.	Current	Voltage
6 AWG	80 Amps	600 VDC
8 AWG	60 Amps	600 VDC

CSA approval meets following standards/test procedures:

a) CSA std. C22.2 No. 182.3

b) UL-1977

• - "C" and "US" mark adjacent to CSA signifies that the product has been evaluated to the applicable CSA and ANSI/UL standards, for use in Canada and US respectively.

## 9.2 U.L. File No. E29179 Rev. 2012-09-24 Volume 10, Sec. 18, Page 1

AWG	Voltage (V)	Current (I)
6	600 AC	80 Amps
8	600 AC	65 Amps
10	600 AC	50 Amps

Flammability - V-0

Note: Approval is at the component level.

#### 9.2.1 Hot-Plug / Overload:

250 Volt AC @ 80 Amps tested to 25 cycles.

REVISION:	ECR/ECN INFORMATION:	TITLE:	Guardian		SHEET No.
C4	EC No: UCP2013-5363	,	Wire to Board		<b>18</b> of <b>19</b>
C4	DATE: 2013/06/12	Inte			
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PA	TEL

TEMPLATE FILENAME: PRODUCT\_SPEC[SIZE\_A](V.1).DOC

## PRODUCT SPECIFICATION

### 9.2.2 HOT-MATE/RESISTANCE TO ARC RATING SYSTEM:

Tested 8 AWG 350 VDC @ 12 Amp. Conducted 50 cycle followed by T-rise max, T-rise is 30°C.

ITEM	TEST DESCR	PTION			RESULT	•	
1	Initial Contact Resistance (Low Level)	6 AWG 8 AWG 10 AWG	See Table 9				
2	Dielectric Withstanding for 60 sec. @ 5mAmp max. per EIA-364-52	1,700 VAC	Pass				
3	Insulation Resistance for 60 sec. @ 500 VDC	1,000 MegOhms	Pass				
4	Current carrying Capability @ 30 degree T-Rise Per EIA-70		6 AWG 8 AWG 10 AWG	1 Ckt (Amps) 80 65 50	2 Ckt (Amps) 77 62 48	3 Ckt (Amps) 73 58 44	4-6Ckt * (Amps) 63 50 35
5	Reliability Test for 6 AWG @ 30 degree T- Rise Max ( 3ckt Power)	70 Amps for 4 days, current cycle for 10 days, 70 amps for 4 additional days	Stable for entire test duration (See 5.3.5 - Fig 7)				
6	Voltage Drop with Step Current applied per EIA 364, TP-06	2 Ckt. With 8 AWG Wire	16 Millivolt drop max (See 5.3.4 - Fig 6)				ig 6)

## 9.2.3 Current Interrupt Rating Per UL-1977 is 30Amps @ 250VAC

REVISION:	ECR/ECN INFORMATION:	TITLE:	Guardian		SHEET No.
C 4	EC No: UCP2013-5363	Wire to Board			<b>19</b> of <b>19</b>
C4	DATE: 2013/06/12	Interconnect System			
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PA	TEL

TEMPLATE FILENAME: PRODUCT\_SPEC[SIZE\_A](V.1).DO